Applications:

The SDRAM test unit designed by Team Valence has been created to serve the needs of Micron Technologies. The portable SDRAM test unit is to be used by Micron for aid in failure analysis. The SDRAM tester writes a user defined test pattern to the SDRAM chip, and reads data back from the chip to verify or analyze any hard fails of the SDRAM chip. All collected data by the PIC controlled test unit is sent back to the PC for feedback to the user. The Visual C++ code displays the failed bits within a graphical representation of the memory array. All data is also written to a file for further analysis. The finished product presented by Team Valence has been designed to meet the requirements specified by Micron Technologies for these purposes only.